

Product Description	High Band LNA With Bypass		
Package Type	QFN, 2.2mmx2.2mmx0.5mm	Process Technology	FET2D
Qualification #	08-QUAL-1032	Date Issued	09/22/2009

FOR IMPORTANT INFORMATION REGARDING THESE MATERIALS INCLUDING DISCLAIMERS REGARDING USE IN CERTAIN APPLICATIONS, SEE STANDARD DISCLAIMER FOR PRODUCT DOCUMENTS.

Test Name		Test Standard and Conditions	Samples Per Lot	Test Results	
D e v i c e	High Temperature Operating Life (DC)	JESD22-A108 125°C, DC bias, 1000 hours	22 x 1 lot	Pass	
	Temperature Humidity with Bias	JESD22-A101 85%RH / 85°C, 500 hours	77 x 1 lot	Pass	
	ESD Human Body Model	JESD22-A114	3 x 1 lot	Pass 500V	ESD Class 1B
	ESD-CDM	JESD22-C101	3 x 1 lot	Pass 350V	ESD Class II
P a c k a g e	Solderability	JESD22-B102, steam age condition C (8hrs.), Dip condition B (245 C. 5 second dwell)	22 x 3 lots	Pass	
	MSL2, 6xreflow	IPC/JEDEC J-STD-020	22 x 3 lots	Pass MSL2 @ 260C	
	Temperature Cycle (MSL2, 6xreflow parts)	JESD22-A104 Condition B -55 +/-125°C, soak mode 1, 500 cycles	22 x 3 lots Use MSL parts	Pass	
Characterization		5515680	5 x 3 lots	Pass	
Conclusion		This product has passed the RFMD Qualification Requirements for production.			

Sample size and lot quantities reported are the minimum required for this qualification.

For additional information please contact your RFMD Customer Quality Engineer.